

International Shopping

DEPARTMENT OF PHYSICS

Tender for Equipment – NITT : 16/2006/TEQIP

Date : 4-10-2006

TPHYIS02-Thickness Measurement System

- Thickness measurement : 150Å to 50µm
- Wavelength Range : 400 to 1000 nm
- Spot size : Adjustable
- Method : Special Reflectance
- Provision to measure optical constants (n and k)
- Complete software with all accessories